IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No
Priority Filing Date October 3, 2002
nventor Luan C. Tran
Assignee Micron Technology, Inc.
Priority Group Art Unit
<u>Priority</u> Examiner Laura M. Schillinger
Attorney's Docket No MI22-2331
Title: Semiconductor Processing Methods of Forming Integrated Circuitry

INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, copending application of the above-identified application. The above-identified application is a divisional of co-pending application Serial No. 10/264,615, filed October 3, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). Copies of the foreign references and publications are provided.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 34/4 //, 2003

Deepak Malhotra Reg. No. 33,560

Wells, St. John, Roberts, Gregory & Matkin P.S.

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Form PTO-1449

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ATTY. DOCKET NO. MI22-2152 SERIAL NO. Unknown

LIST OF ART CITED BY APPLICANT

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APPLICANT
Luan C. Tran

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